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Provisional Data Sheet No. PD-9.426B

急出货

International **IR** Rectifier HEXFET® POWER MOSFET

JANTX2N6788 JANTXV2N6788 [REF:MIL-PRF-19500/555] [GENERIC:IRFF120] N-CHANNEL

100 Volt, 0.30Ω HEXFET

HEXFET technology is the key to International Rectifier's advanced line of power MOSFET transistors. The efficient geometry achieves very low on-state resistance combined with high transconductance.

HEXFET transistors also feature all of the well-established advantages of MOSFETs, such as voltage control, very fast switching, ease of paralleling and electrical parameter temperature stability. They are well-suited for applications such as switching power supplies, motor controls, inverters, choppers, audio amplifiers, and high energy pulse circuits, and virtually any application where high reliability is required.

Product Summary

Part Number	BVDSS	RDS(on)	ID
JANTX2N6788	100V	0.30Ω	6.0A
JANTXV2N6788			

Features:

- Avalanche Energy Rating
- Dynamic dv/dt Rating
- Simple Drive Requirements
- Ease of Parallelizing
- Hermetically Sealed

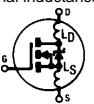
Absolute Maximum Ratings

	Parameter	JANTX2N6788, JANTXV2N6788	Units
I _D @ V _{GS} = 10V, T _C = 25°C	Continuous Drain Current	6.0	A
I _D @ V _{GS} = 10V, T _C = 100°C	Continuous Drain Current	3.5	
I _{DM}	Pulsed Drain Current ①	24	
P _D @ T _C = 25°C	Max. Power Dissipation	20	W
	Linear Derating Factor	0.16	W/K ⑤
V _{GS}	Gate-to-Source Voltage	±20	V
dv/dt	Peak Diode Recovery dv/dt ③	5.5	V/ns
T _J	Operating Junction	-55 to 150	°C
T _{STG}	Storage Temperature Range		
	Lead Temperature	300 (0.063 in. (1.6mm) from case for 10.5 seconds)	
	Weight	0.98 (typical)	g

JANTX2N6788, JANTXV2N6788 Device

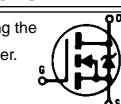
Electrical Characteristics @ $T_j = 25^\circ\text{C}$ (Unless Otherwise Specified)

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	100	—	—	V	$\text{V}_{\text{GS}} = 0\text{V}$, $\text{I}_D = 1.0 \text{ mA}$
$\Delta \text{BV}_{\text{DSS}}/\Delta T_j$	Temperature Coefficient of Breakdown Voltage	—	0.10	—	$\text{V}/^\circ\text{C}$	Reference to 25°C , $\text{I}_D = 1.0 \text{ mA}$
$\text{R}_{\text{DS}(\text{on})}$	Static Drain-to-Source On-State Resistance	—	—	0.30	Ω	$\text{V}_{\text{GS}} = 10\text{V}$, $\text{I}_D = 3.5\text{A}$ ④
		—	—	0.345		$\text{V}_{\text{GS}} = 10\text{V}$, $\text{I}_D = 6.0\text{A}$
$\text{V}_{\text{GS}(\text{th})}$	Gate Threshold Voltage	2.0	—	4.0	V	$\text{V}_{\text{DS}} = \text{V}_{\text{GS}}$, $\text{I}_D = 250\mu\text{A}$
g_{fs}	Forward Transconductance	1.5	—	—	$\text{S } (\text{t})$	$\text{V}_{\text{DS}} > 15\text{V}$, $\text{I}_{\text{DS}} = 3.5\text{A}$ ④
IDSS	Zero Gate Voltage Drain Current	—	—	25	μA	$\text{V}_{\text{DS}} = 0.8 \times \text{Max Rating}$, $\text{V}_{\text{GS}} = 0\text{V}$
		—	—	250		$\text{V}_{\text{DS}} = 0.8 \times \text{Max Rating}$ $\text{V}_{\text{GS}} = 0\text{V}$, $T_j = 125^\circ\text{C}$
IG_{SS}	Gate-to-Source Leakage Forward	—	—	100	nA	$\text{V}_{\text{GS}} = 20\text{V}$
IG_{SS}	Gate-to-Source Leakage Reverse	—	—	-100		$\text{V}_{\text{GS}} = -20\text{V}$
Q_{g}	Total Gate Charge	7.7	—	17	nC	$\text{V}_{\text{GS}} = 10\text{V}$, $\text{I}_D = 6.0\text{A}$
Q_{gs}	Gate-to-Source Charge	0.7	—	4.0		$\text{V}_{\text{DS}} = \text{Max. Rating} \times 0.5$ see figures 6 and 13
Q_{gd}	Gate-to-Drain ("Miller") Charge	2.0	—	7.7	ns	$\text{V}_{\text{DD}} = 50\text{V}$, $\text{I}_D = 6.0\text{A}$, $\text{R}_G = 7.5\Omega$, $\text{V}_{\text{GS}} = 10\text{V}$ see figure 10
$t_{\text{d}(\text{on})}$	Turn-On Delay Time	—	—	40		
t_{r}	Rise Time	—	—	70		
$t_{\text{d}(\text{off})}$	Turn-Off Delay Time	—	—	40		
t_{f}	Fall Time	—	—	70		
L_{D}	Internal Drain Inductance	—	5.0	—	nH	Measured from the drain lead, 6mm (0.25 in.) from package to center of die.
L_{S}	Internal Source Inductance	—	15	—		Measured from the source lead, 6mm (0.25 in.) from package to source bonding pad.
C_{iss}	Input Capacitance	—	350	—	pF	$\text{V}_{\text{GS}} = 0\text{V}$, $\text{V}_{\text{DS}} = 25\text{V}$
C_{oss}	Output Capacitance	—	150	—		$f = 1.0 \text{ MHz}$
C_{rss}	Reverse Transfer Capacitance	—	24	—		see figure 5



Source-Drain Diode Ratings and Characteristics

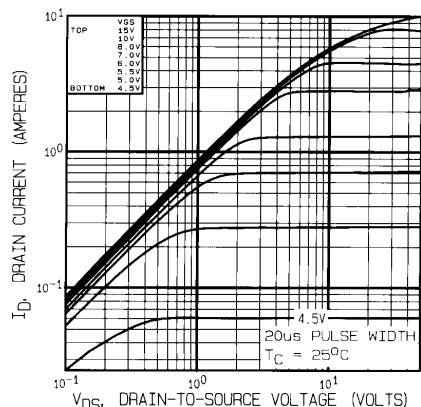
	Parameter	Min.	Typ.	Max.	Units	Test Conditions
I_{S}	Continuous Source Current (Body Diode)	—	—	6.0	A	Modified MOSFET symbol showing the integral reverse p-n junction rectifier.
I_{SM}	Pulse Source Current (Body Diode) ①	—	—	24		
V_{SD}	Diode Forward Voltage	—	—	1.8	V	$T_j = 25^\circ\text{C}$, $\text{I}_{\text{S}} = 6.0\text{A}$, $\text{V}_{\text{GS}} = 0\text{V}$ ④
t_{rr}	Reverse Recovery Time	—	—	240	ns	$T_j = 25^\circ\text{C}$, $\text{I}_{\text{F}} = 6.0\text{A}$, $d\text{I}/dt \leq 100\text{A}/\mu\text{s}$
Q_{RR}	Reverse Recovery Charge	—	—	2.0	μC	$\text{V}_{\text{DD}} \leq 50\text{V}$ ④
t_{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible. Turn-on speed is substantially controlled by $\text{L}_{\text{S}} + \text{L}_{\text{D}}$.				



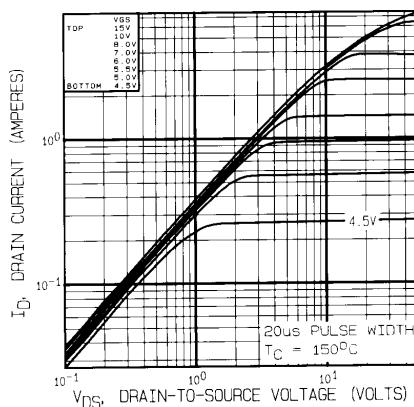
Thermal Resistance

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
R_{thJC}	Junction-to-Case	—	—	6.25	K/W	Typical socket mount
R_{thJA}	Junction-to-Ambient	—	—	175		

JANTX2N6788, JANTXV2N6788 Device



**Fig. 1 — Typical Output Characteristics
 $T_C = 25^\circ\text{C}$**



**Fig. 2 — Typical Output Characteristics
 $T_C = 150^\circ\text{C}$**

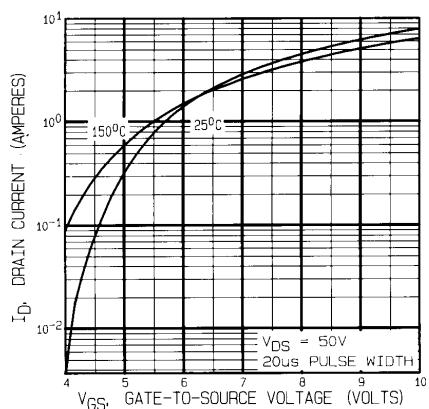


Fig. 3 — Typical Transfer Characteristics

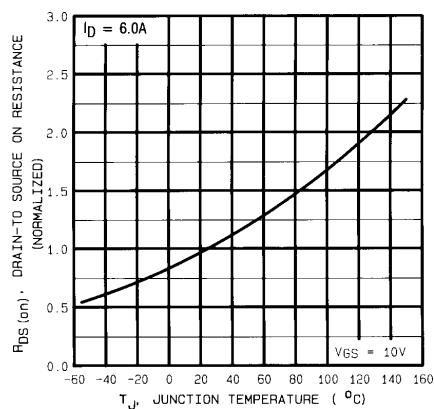


Fig. 4 — Normalized On-Resistance Vs.Temperature

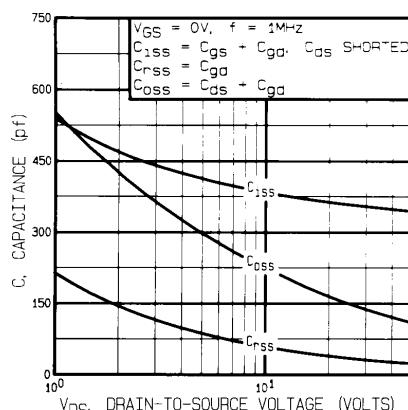


Fig. 5 — Typical Capacitance Vs. Drain-to-Source Voltage

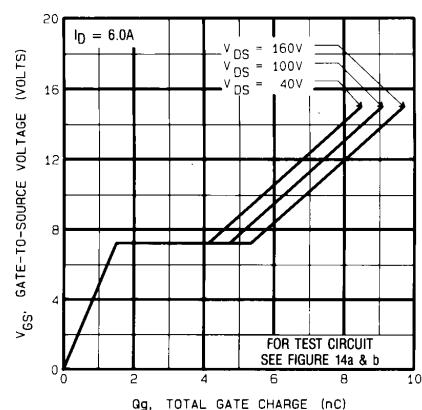


Fig. 6 — Typical Gate Charge Vs. Gate-to-Source Voltage

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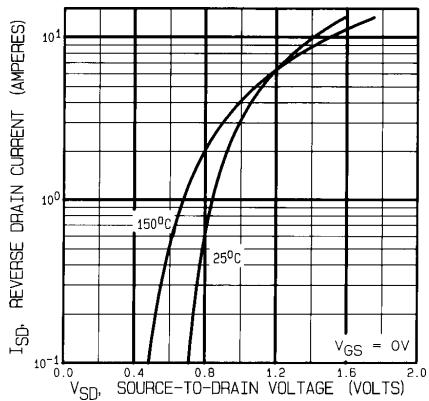


Fig. 7 — Typical Source-to-Drain Diode Forward Voltage

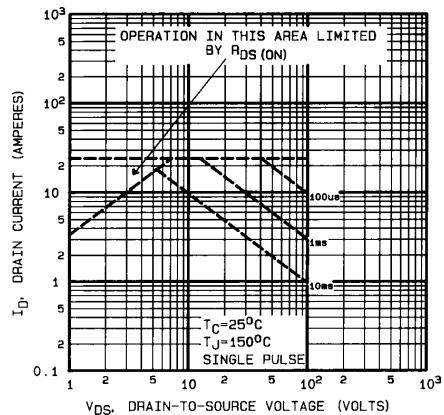


Fig. 8 — Maximum Safe Operating Area

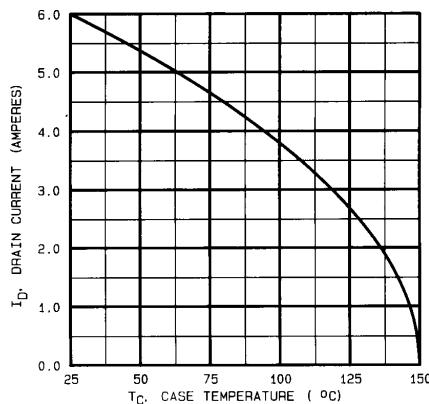


Fig. 9 — Maximum Drain Current Vs. Case Temperature

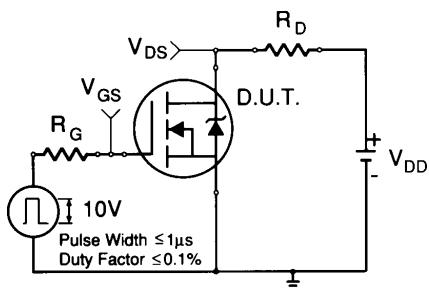


Fig. 10a — Switching Time Test Circuit

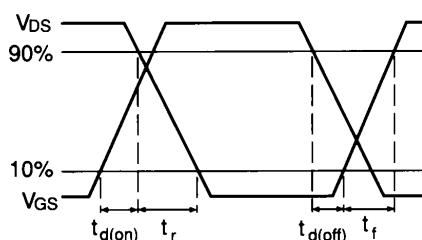


Fig. 10b — Switching Time Waveforms

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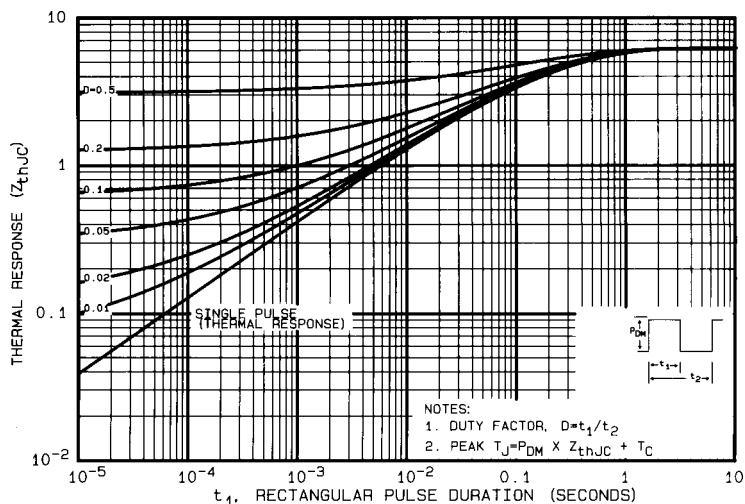


Fig. 11 — Maximum Effective Transient Thermal Impedance, Junction-to-Case Vs. Pulse Duration

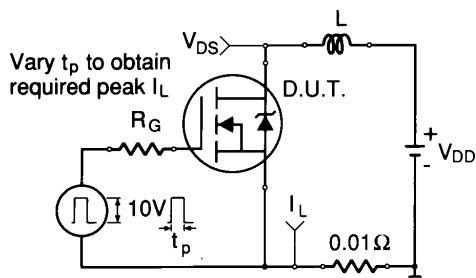


Fig. 12a — Unclamped Inductive Test Circuit

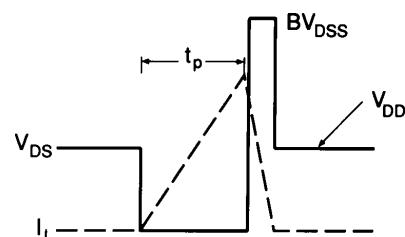


Fig. 12b — Unclamped Inductive Waveforms

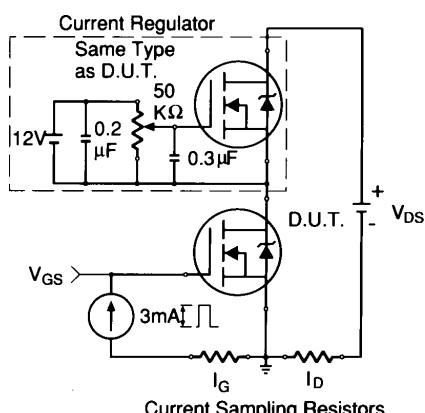


Fig. 13a — Gate Charge Test Circuit

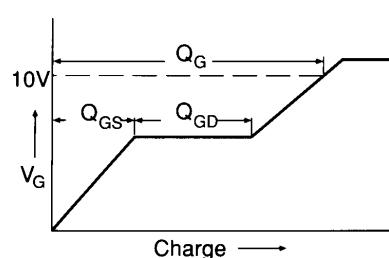
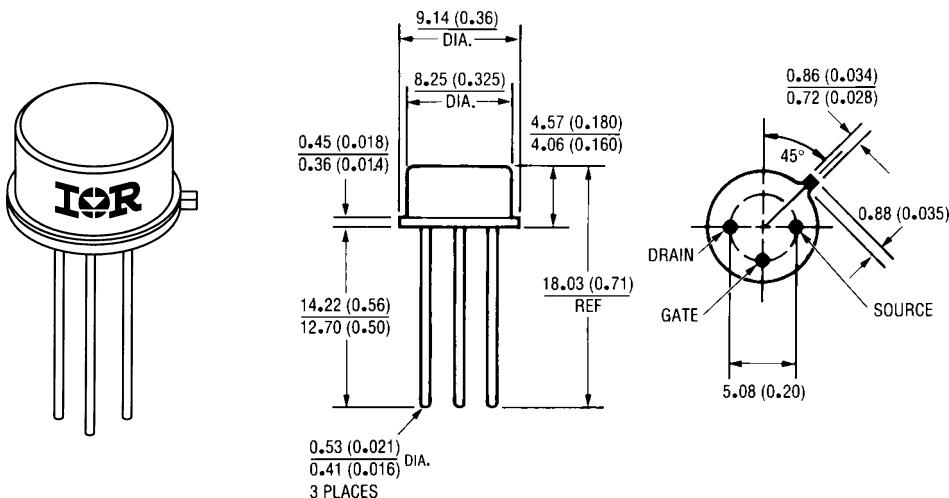


Fig. 13b — Basic Gate Charge Waveform

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- ① Repetitive Rating; Pulse width limited by maximum junction temperature.
(see figure 11)
- ② @ $V_{DD} = 25V$, Starting $T_J = 25^\circ C$,
 $EAS = [0.5 * L * (I_L^2) * [BV_{DSS}/(BV_{DSS}-V_{DD})]$
 Peak $I_L = 6.0A$, $V_{GS} = 10V$, $25 \leq R_G \leq 200\Omega$
- ③ $ISD \leq 6.0A$, $dI/dt \leq 110A/\mu s$,
 $V_{DD} \leq BV_{DSS}$, $T_J \leq 150^\circ C$
- ④ Pulse width $\leq 300 \mu s$; Duty Cycle $\leq 2\%$
- ⑤ $K/W = ^\circ C/W$
 $W/K = W/^{\circ}C$

Case Outline and Dimensions — TO-205AF (Modified TO-39)



All dimensions are shown millimeters (inches)

International
IR Rectifier

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